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PATENT NUMBER and
ISSUE DATE.

U.S. UTILITY Patent Application

APPL NUM 10046559	FILING DATE 10/27/2001	CLASS 324	SUBCLASS 158.1	GAU 2862	EXAMINER Jimmie - Nguyen
**APPLICANTS: Strom John; 2823					
**CONTINUING DATA VERIFIED: THIS APPLN CLAIMS BENEFIT OF 60/244,432 10/30/2000					
** FOREIGN APPLICATIONS VERIFIED:					
PG-PUB <input type="checkbox"/> DO NOT PUBLISH <input type="checkbox"/>		RESCIND <input type="checkbox"/>			
Foreign priority claimed <input type="checkbox"/> yes <input type="checkbox"/> no 35 USC 119 conditions met <input type="checkbox"/> yes <input type="checkbox"/> no Verified and Acknowledged Examiner's initials				ATTORNEY DOCKET NO 11532-014001	
TITLE : Method and process of applying the analysis of scrub mark morphology and location to the evaluation and correction of semiconductor testing analysis, and manufacture					
<small>U.S. DEPT. OF COMM./PAT. & TM-PTO-4361 (Rev. 12-94)</small>					

NOTICE OF ALLOWANCE MAILED		Assistant Examiner	CLAIMS ALLOWED	
			Total Claims	Print Claim for O.G.
ISSUE FEE		Primary Examiner	DRAWING	
Amount Due	Date Paid		Sheets Drawg.	Figs. Drawg.
<input type="checkbox"/> TERMINAL DISCLAIMER		PREPARED FOR ISSUE	Application Examiner	
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